

<b>Notice of References Cited</b>	Application/Control No. 10/721,745	Applicant(s)/Patent Under Reexamination HEDLER ET AL.	
	Examiner Yennhu B. Huynh	Art Unit 2813	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,140,707	10-2000	Plepys et al.	257/778
	B	US-6,573,598 B2	06-2003	Ohuchi et al.	257/734
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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